

BS ISO 17901-1:2015



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Optics and photonics — Holography

Part 1: Methods of measuring diffraction efficiency and associated optical characteristics of holograms

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National foreword

This British Standard is the UK implementation of ISO 17901-1:2015.

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A list of organizations represented on this committee can be obtained on request to its secretary.

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Part 1:
Methods of measuring diffraction
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Optique et photonique — Holographie —

Partie 1: Méthodes de mesure de l'efficacité de diffraction et
caractéristiques optiques associées aux hologrammes





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Foreword

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The committee responsible for this document is ISO/TC 172, *Optics and Photonics*, Subcommittee SC 9, *Electro-optical systems*.

ISO 17901 consists of the following parts, under the general title *Optics and photonics — Holography*:

- *Part 1: Methods of measuring diffraction efficiency and associated optical characteristics of holograms*
- *Part 2: Methods for measurement of hologram recording characteristics*

Introduction

The aim of this part of ISO 17901 is to specify the terms related to holograms and basic measurement methods to characterize them.

A hologram is an optical device utilizing interference and diffraction phenomena and is characterized differently from optical devices based on reflection, refraction, and scattering. By exploiting the characteristics of holograms, they have been successfully applied in numerous applications such as displays, metrology, and anti-counterfeit security.

The expanded market in holography has generated a need to agree on basic terms and definitions for holograms and measurement methods and this part of ISO 17901 aims to satisfy that need.

